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Phototransferred TL properties of alumina substrates

Lily Bossin, Ian K. Bailiff, Ian Terry

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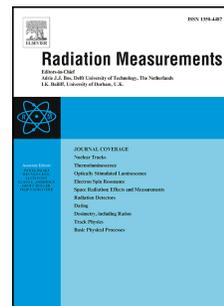
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Lily Bossin^{a,b,c,*}, Ian K. Bailiff^a, Ian Terry^b^a*Department of Archaeology, Durham University, UK*^b*Department of Physics, Durham University, UK*^c*Radiation Metrology, Public Health England, Didcot, UK*

Abstract

Alumina substrates, such as those found as surface-mount resistors in mobile phones, are currently the strongest candidate as a surrogate dosimeter material in emergency radiological scenarios using luminescence techniques. However, the rate of fading of the luminescence signal (TL or OSL) imposes a limitation on their longer term use, and also increases the uncertainty in dose assessment. The potential of phototransferred thermoluminescence (PTTL) techniques to access deep traps in alumina substrate samples is reported here. A measurement procedure employing blue (470 nm) illumination was found to produce a PTTL signal with a detection limit of ca 100 mGy, but with a supralinear dose response below 10 Gy. By using a UV source with emission between 307 - 575 nm a linear dose response was obtained within this dose range, although the detection limit was higher (ca 200 mGy), partly arising from the presence of a non-radiation-induced photostimulated TL signal. Pulse annealing experiments indicate that deep traps providing a reservoir of charge are thermally accessible above 500 °C and require annealing to ca 700 °C to thermally clean them. Significantly, using blue illumination, storage experiments performed under dark conditions at room temperature indicate that the loss of charge in the deep traps accessed by the PTTL measurement procedure was less than 30% for storage periods of up to 224 days. Although the physical mechanisms associated with the transfer of charge from the deep traps probed by the PTTL measurements require further clarification, the possibility of significantly reducing the fading observed in conventional TL or OSL measurements introduces a potentially valuable tool in the use of this material for both short and long term dosimetry.

Keywords: Alumina substrate, Phototransferred thermoluminescence, Emergency dosimetry

1. Introduction

The measurement of phototransferred thermoluminescence (PTTL) is a well-established procedure used as a means to access deep traps in luminescent minerals and phosphors. This is achieved by moving a proportion of charge stored in deep traps to previously thermally cleaned shallower traps, typically by using short wavelength optical stimulation. Prompt measurement of the resultant PTTL glow curve enables an indirect measurement of the population of charges in the deep traps. PTTL procedures have been developed for variety of materials, including lithium fluoride (Kharita et al. 1994; Charles 1983), quartz (Bailiff et al., 1977) and aluminium oxide (Akselrod and Gorelova 1993; Colyott et al. 1996; Bulur and Göksu 1999; Polymeris and Kitis 2012; Nyirenda et al. 2016; Chithambo et al. 2017). The primary advantage of using this procedure is to avoid the effects of interfering black-body radiation and thermal quenching where the thermoluminescence (TL) peaks associated

*Corresponding author: lily.bossin@durham.ac.uk

11 with the deep traps are measured directly (i.e., ≥ 500 °C). Also, the PTTL may potentially provide a means of
12 circumventing the effects of anomalous fading (Bailliff 1976; McKeever et al. 2017).

13 Alumina that forms the substrate of surface-mount resistors, which is structurally the polycrystalline ana-
14 logue of aluminium oxide, has been widely studied as a dosimetry material for use in emergency scenarios (Inrig
15 et al. 2008; Bassinet et al. 2014). Its TL properties are favourable for dosimetry, with a strong TL signal,
16 linearity of dose response and a detection limit of ~ 10 mGy (Woda et al. 2009; Mesterhzy et al. 2012). How-
17 ever, fading in regions of the TL glow curve where loss at room temperature (RT) is expected to be negligible
18 (300-450 °C, ca 23% loss in 20 days) is a known problem that has been attributed to athermal loss of charge.
19 Although the luminescent characteristics of alumina substrate have been examined in depth (Kouroukla 2015;
20 Ademola and Woda 2017; Bassinet et al. 2010), an investigation of its PTTL characteristics does not appear
21 to have been reported, although observation of an intrinsic photostimulated (PSTL) response stimulated by
22 the UV illumination of alumina resistor substrates that is not related to absorbed dose was recently reported
23 by Ademola and Woda (2017). In this study we applied a PTTL measurement procedure to investigate the
24 presence of deep traps in polycrystalline alumina substrates and to assess whether PTTL provides an advantage
25 in terms of application to longer-term dosimetry.

26 2. Experimental

27 All OSL and TL measurements were performed with a Risø model 12 reader (DTU Nutech, Denmark) that
28 incorporates a $\text{Sr}^{90}/\text{Y}^{90}$ β source irradiator delivering an estimated dose rate to alumina substrates of 0.74
29 $\text{Gy}\cdot\text{min}^{-1}$. A UV (250-350 nm; Schott U-340 filter) and a broad band (360 - 580 nm; Schott BG-39 filter)
30 detection windows were used when measuring blue (470 nm) stimulated OSL and TL. Two illumination sources
31 were employed to transfer charge from deep traps for the PTTL measurements, comprising either the 470 nm
32 LEDs in the Risø reader, delivering a power of $14 \text{ mW}\cdot\text{cm}^{-2}$ at the sample position, or UV radiation from
33 an unfiltered medium - pressure mercury lamp. The mercury lamp (Hanovia Ltd) delivered a power of ~ 4
34 $\text{mW}\cdot\text{cm}^{-2}$ at the sample position and its emission spectrum contained lines at 307, 364, 403, 434, 544 and 575
35 nm. The abbreviated terms PTTL[UV] and PTTL[470 nm] are used to distinguish the type of illumination
36 source used to obtain the PTTL. For each set of measurements, five alumina substrate surface-mount resistors of
37 type 1206 (RS pro, $\sim 5.2 \text{ mm}^2$), were placed in a stainless steel cup with the alumina substrate layer facing up,
38 and each test was repeated at least twice to test for reproducibility. The TL peak temperatures were calculated
39 by applying a deconvolution procedure to the measured glow curve data (using Origin 2017) and hence the
40 values obtained reflect the precision of the fitting procedure only. Independent thermocouple measurements of
41 the heater plate temperature indicated that the temperatures displayed by the Viewer software (DTU Nutech)
42 are within 6 °C of the measured value and that, when taking into account thermal lag introduced by the samples
43 and the stainless steel pans, the overall uncertainty in the average resistor temperature is likely to be the order
44 of ± 8 °C. The PTTL (470 nm) measurement procedure (A) followed is summarised in Table 1.

45 3. PTTL characteristics

46 3.1. Detection window

47 Measurements performed using the BG-39 detection filter yielded a PTTL[470 nm] signal about three times
48 stronger (Fig. 1) than with a U-340 filter, indicating that the PTTL emission spectrum is not confined to

Step	Measurement
1	TL to T_{stop} 450 °C (procedure A) or 500 °C (procedure B); 5 °C.s ⁻¹
2	Repeat step 1 (background); subtraction of the background from the TL glow curve (step 1)
3	Phototransfer illumination, 470 nm LEDs, 120 s at sample temp. of 150 °C; concurrent measurement of OSL
4	PTTL to T_{stop} (500 °C); 0.5 °C.s ⁻¹
5	Repeat step 4 (background); subtraction of the background from the PTTL glow curve (step 4)
6	Anneal to 700 °C in a furnace, in air, 20 min

49 the UV region. This is consistent with radioluminescence (RL) spectra measured with alumina substrates by
50 Kouroukla (2015, p. 132) and Lee et al. (2017) which indicated complex emission that included UV, blue and
51 red bands. It was also observed that the intensity of the shorter wavelength emissions was thermally quenched,
52 giving rise to predominantly red emission at higher temperatures (Kouroukla, 2015, p. 132). However, recording
53 the red TL emission above 400 °C using the BG-39 gave rise to a strong thermal background signal, making
54 the detection of weak signals associated with low dose difficult to resolve above the thermal background signal.

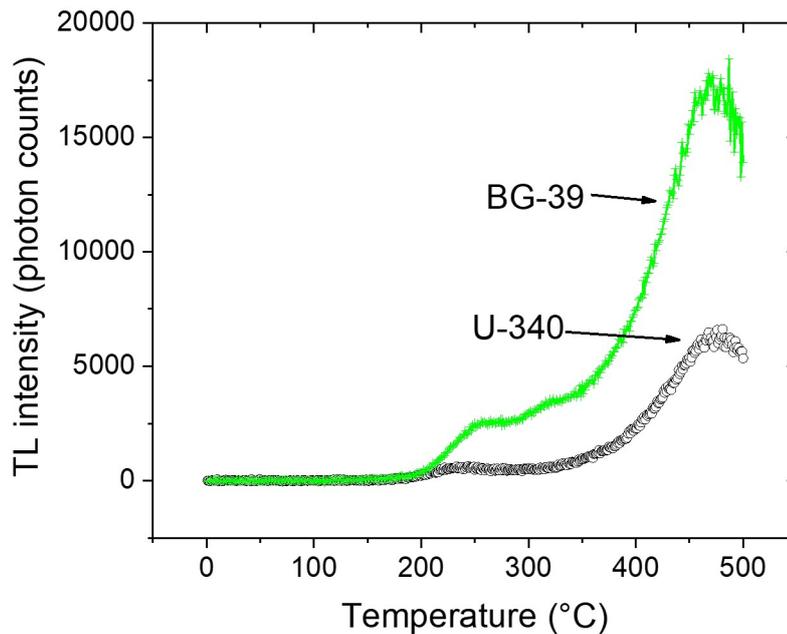


Fig. 1. PTTL[470 nm] glow curves measured with alumina substrate chips following β irradiation (10 Gy). Detection window: U-340 (black curve) and BG-39 (green curve); heating rate 0.5 °C.s⁻¹. The thermal background signal was subtracted.

55 3.2. Variation of PTTL with sample temperature

56 The PTTL (470 nm) glow curve was recorded following a 2 min 470 nm exposure (concurrently measuring
57 the OSL) at a sample temperature selected in the range 50-400 °C (Fig. 2). The shape of the PTTL glow curve
58 changes with the sample temperature during illumination and, as the temperature increases, a more efficient
59 transfer of charge to shallower traps gives rise to relatively stronger lower temperature PTTL peaks. Above
60 200 °C the transfer process competes with thermal bleaching of the PTTL traps during illumination, leading

61 to a progressive decrease of the PTTL signal. A similar measurement procedure was applied by varying the
 62 illumination time (30-300 s) for a fixed sample temperature. A plot of the integral of the PTTL glow curve
 63 (150-500 °C) vs both sample temperature and duration of illumination, shown in the form of a contour plot in
 64 Fig. 3, indicates that the maximum PTTL intensity was obtained for an illumination of 2 mins with a sample
 65 temperature of 150 °C, and these measurement conditions were adopted using procedure A (Table 1).

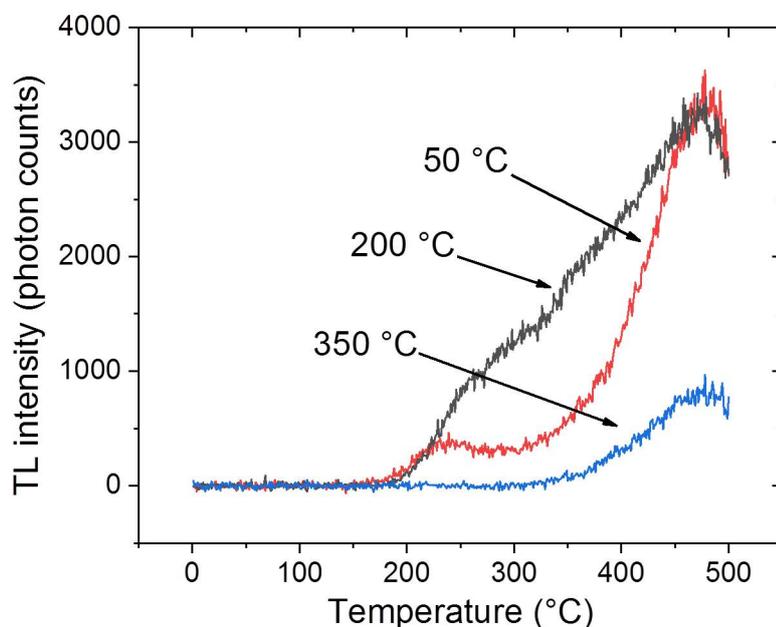


Fig. 2. Phototransferred TL glow curves of alumina substrate measured following a β irradiation (10 Gy), a 2 mins 470 nm illumination at a sample temperature in the range 50-350 °C, three examples of which (50, 200 and 350 °C) are shown. Detection filter: U-340; heating rate 0.5 °C.s⁻¹.

66 3.3. Dose response

67 The PTTL (470 nm) glow curve contains several overlapping peaks (Fig. 4a), positioned at 190, 240, 335 and
 68 465 °C. The presence of a native signal was tested by measuring a fresh set of unirradiated resistors, but found
 69 to be negligible using 470 nm illumination (Fig. 4a). Fig. 4b shows the growth of the PTTL peaks (integrated
 70 TL, 150 -500 °C) with absorbed β dose, measured with the same aliquot, which exhibits a supralinear dose
 71 dependence (Fig. 4b) that was also observed for each peak analysed individually. Two preheat temperatures
 72 were tested : 450 °C (procedure A) and 500 °C (procedure B), using a heating rate of 0.5 °C.s⁻¹. An additional
 73 TL background measured after step 2 in procedure B indicated that some residual TL remained after this step
 74 (see Supplementary Material) above 300 °C (Procedure A) or 350 °C (Procedure B). The integration region
 75 of the PTTL glow curve was between 150-300 °C to avoid this residual TL. The glow curves measured using
 76 procedures A and B contained similar peaks but the signal was weaker using procedure B, although the dose
 77 response appeared to be more linear. Interestingly, similar analysis performed using an integration range of
 78 300-500 °C produced similar outcomes.

79 The reproducibility of the PTTL signal, tested by repeating procedure A five times for a given dose, exhibited
 80 similar values of integrated photon counts (within 10 %). Using procedure A, and a quadratic function fitted
 81 to the dose response data, the detection limit (calculated as the dose for which the PTTL signal is equal to the

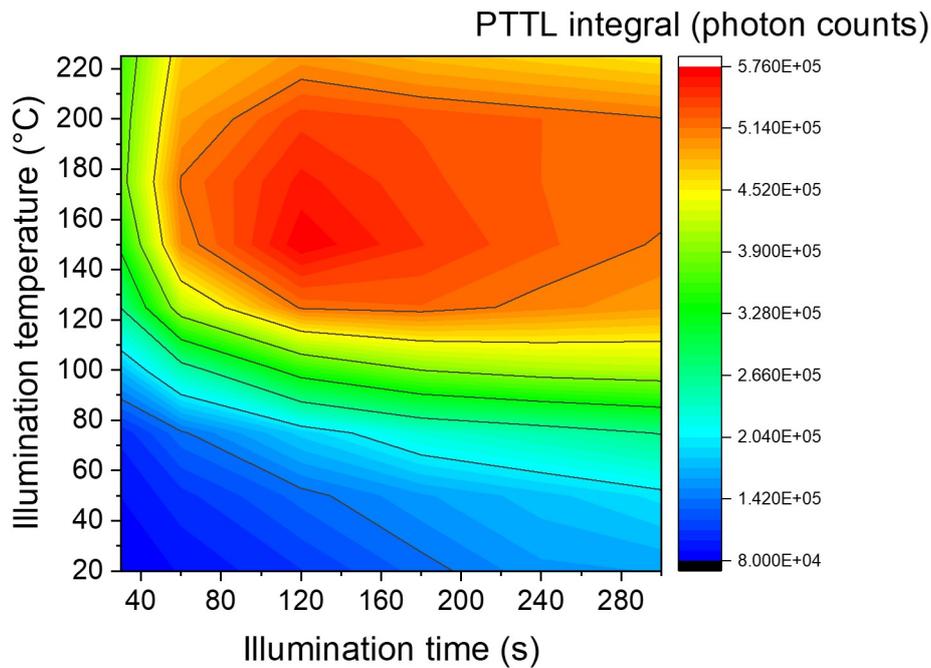


Fig. 3. “Map” of PTTL intensity vs the illumination parameters (duration and temperature). The PTTL intensity corresponds to the integral of the signal recorded between 150 and 500 °C.

82 background signal plus three times its standard deviation) was estimated to be ~ 100 mGy. The final annealing
 83 step (6) was applied to minimise sensitization effects by thermally cleaning the deep electron traps. If this step
 84 is omitted, a non-linear increase in sensitivity is observed over repeated cycles of measurements. During 470
 85 nm illumination at elevated sample temperatures (Step 3), the OSL signal was also recorded (Fig. 5) and its
 86 slow evolution and subsequent decay reflect a thermally-assisted process (TA-OSL), similar to that observed
 87 with $\text{Al}_2\text{O}_3:\text{C}$ (Polymeris et al., 2010), together a supralinear dependence with dose (not shown).

88 4. Kinetic parameters of the reservoir traps

89 A pulse-annealing stage was added to procedure A to examine the thermal stability of the traps that provide
 90 a reservoir of charge for the PTTL signal. The samples were heated to a temperature selected in the range 450
 91 to 600 °C before the 470 nm illumination in Step 3 and subsequent recording of the PTTL to 500 °C. During
 92 the pulse-annealing sequence, the 480 °C PTTL peak exhibited the strongest reduction (Fig. 6a and 6b) in
 93 intensity following a preheat to 600 °C, indicating that charges in deep traps accessed by 470 nm illumination
 94 are thermally emptied by annealing in the region 450-600 °C. Similar results were obtained testing a second set
 95 of chips. Attempts to determine the thermal activation energies of the traps acting as the reservoir of charge
 96 were unsuccessful. An assessment of the Arrhenius plots obtained with data produced from a pulse annealing
 97 PTTL (470 nm) measurement procedure indicated that the nature of these traps is complex, likely to comprise
 98 a continuum of traps associated with TL peaks between 500 and 600 °C.

99 5. UV illumination

100 As the supralinear dose response of the PTTL[470 nm] is a potential disadvantage for absorbed dose determi-
 101 nations below ca 0.5 Gy, optimisation of the PTTL response was explored using shorter wavelength illumination.

102 In contrast to the PTTL[470 nm] results, fresh unirradiated samples, when illuminated (2 mins) with UV pro-
103 duced a “native” glow curve containing two peaks (Fig. 7a). The native signal measured after UV illumination is
104 interpreted as a non-radiation-induced UV-stimulated signal, which is observed, for example, with $\text{Al}_2\text{O}_3\text{:Si,Ti}$,
105 and applied in UV dosimetry (referred to as photo-stimulated TL, PSTL; Mehta and Sengupta 1977, 1978). A
106 PSTL contribution, if present, needs to be accounted for when applying PTTL to perform dosimetry measure-
107 ments with a UV light source. The PTTL (UV) glow curve recorded following a β dose of 10 Gy and a 2 min
108 illumination at RT, contains three main peaks (Fig. 7a) at ca 190, 315 and 460 °C, and the PTTL (470 nm)
109 glow curve is shown for comparison. Under the particular illumination conditions used in these experiments,
110 UV transfers significantly more charge into the PTTL traps compared with 470 nm illumination (the integrated
111 PTTL is ~ 4 times greater for a 10 Gy β dose). By annealing the samples at 900 °C for 30 mins and repeating
112 the PTTL measurement procedure, the glow curve measured was similar in shape and intensity to the “native”
113 PSTL signal. The latter indicates that this annealing procedure effectively thermally cleaned the deep traps
114 associated with the PTTL signal. The dose response curve obtained with UV illumination is linear (Fig. 7b),
115 and the estimated detection limit of 200 mGy is higher than that obtained with 470 nm illumination.

116 6. Fading

117 Fading tests were performed by irradiating samples with a β dose of 7.4 Gy, storage in the dark at ambient
118 room temperature for periods ranging from 6 h to 224 days and measuring the PTTL (470 nm) following
119 procedures A and B and using a integration interval of 150-300 °C. The resistors used in the fading experiments
120 were obtained from the same manufacturer (RS Pro, UK), but they were obtained from two reels, referred to
121 as batches 1 and 2. Measurements using four sets of 5 resistors from Batch 1 were initially conducted with
122 single aliquots for storage periods of 0.125, 2 and ca 100 days, and the tests were repeated using aliquots that
123 contained resistors from both batches (1 and 2), for storage periods up to 2 days and for various storage periods
124 between 2 and 244 days. The results obtained from the fading tests shown in Fig. 8 include: a) the integrated
125 PTTL (150-300 °C) recorded using procedures A (open diamonds) and B (open triangles) b) the integrated TL
126 recorded in two temperature regions (filled circles, 150-200 °C and filled squares, 200-300 °C).

127 It can be seen that using the Batch 1 resistors, the extent of long-term fading over 100 days is less than
128 ca 15%, using either of procedures A and B. Analysing the results using an integration range of 300-500 °C in
129 the PTTL glow curve produced a similar outcome, and suggests that the inclusion of remnant TL in the higher
130 temperature region of the PTTL glow curve does not appear to significantly affect the rate of fading. Although
131 the repeated tests performed with resistors from the combined batches show similar behaviour for storage
132 periods up to 2 days, a greater degree of fading for longer periods of storage is evident in these subsequent tests.
133 Assuming that the measurement procedures were applied correctly, these results provide an alert to the possible
134 variability of fading characteristics between batches of resistors, and this requires more detailed investigation.
135 Nevertheless, the loss observed in these tests at ca 200 days remains some 30% less for PTTL than that obtained
136 with conventional TL, as measured with resistors from the same batches (Fig. 8, filled circles and filled squares),
137 and also obtained in previous studies (Ademola and Woda 2017; Kouroukla 2015).

138 The fading behaviour of the TA-OSL signal was also found to be similar to that of the PTTL. In her study
139 of the long-term fading of OSL of alumina substrate, Geber-Bergstrand (2017) also found the existence of a
140 long-lived OSL component of the decay curve, where the average period after which the signal halved was 790

141 ± 210 days; she estimated that a 0.5 Gy dose could be measured after a period of 2 years, after applying a
142 fading correction.

143 7. Discussion

144 The results of the pulse annealing and phototransfer experiments confirm the presence of deep traps that
145 provide a reservoir of charge probed by the PTTL measurement procedure. If we examine for parallels between
146 the PTTL behaviour of alumina substrates and crystalline Al_2O_3 , amongst the earlier work on the latter,
147 Akselrod and Gorelova (1993) proposed three types of traps that, in addition to type I traps producing the
148 main dosimetry TL peak at 190 °C, included deep type II and type III traps associated with TL peaks at
149 550 °C and ca 900 °C respectively. Colyott et al. (1997) studied three PTTL peaks located at -8, 37 and 177
150 °C measured following preheat treatments ranging from RT to 900 °C, and they found the PTTL to be most
151 efficiently produced when induced by 300 nm illumination. Later work has linked the PTTL with one or more
152 traps associated with TL peaks above 500 °C (Bulur and Göksu, 1999) and above 600 °C (Chithambo et al.,
153 2017). Although the nature of the traps providing the reservoir of charge for PTTL in Al_2O_3 has not been
154 identified, these studies point to the type II and III traps proposed by Akselrod and Gorelova as providing
155 the most likely reservoirs of charge. The results obtained with our alumina substrate samples using 470 nm
156 illumination indicate that the reservoir of charge may originate mainly from traps of similar depth to the type
157 II traps, and under UV illumination (≥ 300 nm) they are likely to be associated with both type II and type III
158 traps, given that annealing at ca 900 °C was required to erase the PTTL (UV) signal. As found with alumina
159 substrate, sensitization effects were reported in monocrystalline Al_2O_3 by Yukihara et al. (2003), and explained
160 by the presence of deeper traps.

161 In addition to characterisation of the deep traps, the nature of the traps into which the charge is trans-
162 ferred associated with the PTTL is also of interest. Again, seeking parallels with crystalline aluminium oxide,
163 Chithambo et al. (2017) found that the peaks in the PTTL and TL glow curves were similar, suggesting that
164 similar traps participate in both modes of measurement. We have made broadly similar observations with the
165 alumina substrate tested, although the distribution of charge in the traps participating in the PTTL and TL
166 processes differ (Fig. 9), with the lower temperature peak more prominent in the glow curve. In the higher
167 temperature region, the 314 and 480 °C TL peaks are reproduced in the PTTL[470 nm] and PTTL[UV] glow
168 curves and the 260 °C TL peak is also present in the PTTL[470 nm] glow curve. However, the 197 °C peak
169 observed in the PSTL and the PTTL[470 nm; UV] glow curves differs in position relative to the main TL peak
170 (165 °C).

171 8. Conclusion

172 The results obtained indicate that PTTL measurement procedures can be applied to polycrystalline Al_2O_3
173 substrates for dose determination using blue and shorter wavelength illumination. For the substrates tested,
174 and using blue illumination, the dose response was found to be supralinear, with a detection limit of ca 100
175 mGy for a resistor surface area of 22.5 mm². By employing UV illumination (≥ 300 nm) the dose response
176 obtained was linear, although with a higher detection limit of ca 200 mGy, partly arising from the presence of a
177 photo-stimulated thermoluminescence (PSTL) signal. The trapped charge transferred in the PTTL procedure
178 originates from deep traps and although their depths could not be determined using blue illumination, we

179 conclude that 1) the trapped charge associated with the PTTL signal originates from a range of deep traps
180 that are thermally erased in the region 450-600 °C and 2) UV illumination enables access to charge in deeper
181 traps that are thermally erased by heating to 900 °C. Significantly, we found that in laboratory fading tests in
182 the dark at room temperature the measured loss of PTTL was less than 30 % for storage periods of up to 224
183 days. This is to be compared with a typical loss of 47 % in 50 days using conventional TL (Ademola and Woda
184 2017; Kouroukla 2015). The PTTL procedure has sufficient sensitivity for dosimetry measurements following
185 radiological emergencies, although further optimisation of the procedure would be required to address the issue
186 of the trend of the decreasing size of surface mount resistors. Although the physical mechanisms associated with
187 the deep traps in the alumina substrate probed by the PTTL measurements require further clarification, the
188 possibility of reducing the extent of the significant fading observed in conventional TL or OSL measurements
189 introduces a potentially valuable tool in the use of this material for short and long term dosimetry.

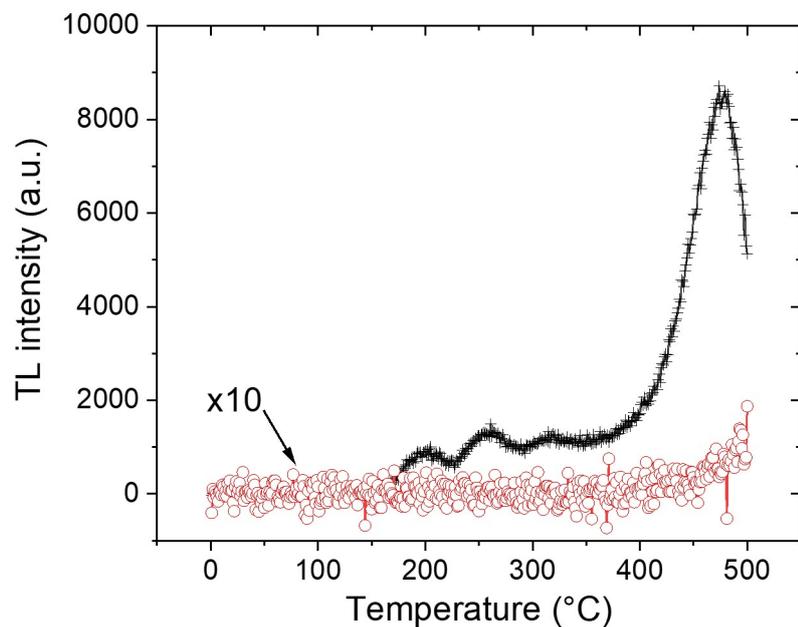
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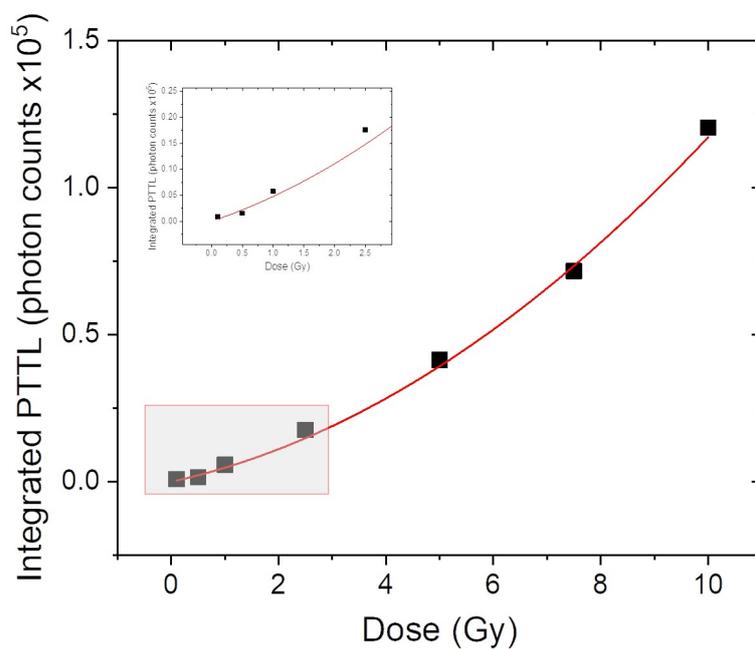
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(a)



(b)

Fig. 4. a) Native (open circle) and β -induced (10 Gy; black cross) PTTL glow curve of five alumina substrate chips, measured following the PTTL procedure (Table 1). Photon count recorded every second; b) Integral of the PTTL signal (150-300 °C) vs administered β dose, where the solid line represents a quadratic curve fitted to the experimental data. Type A error in counts ≤ 1 %. Detection window: U-340; heating rate $0.5 \text{ }^\circ\text{C}\cdot\text{s}^{-1}$.

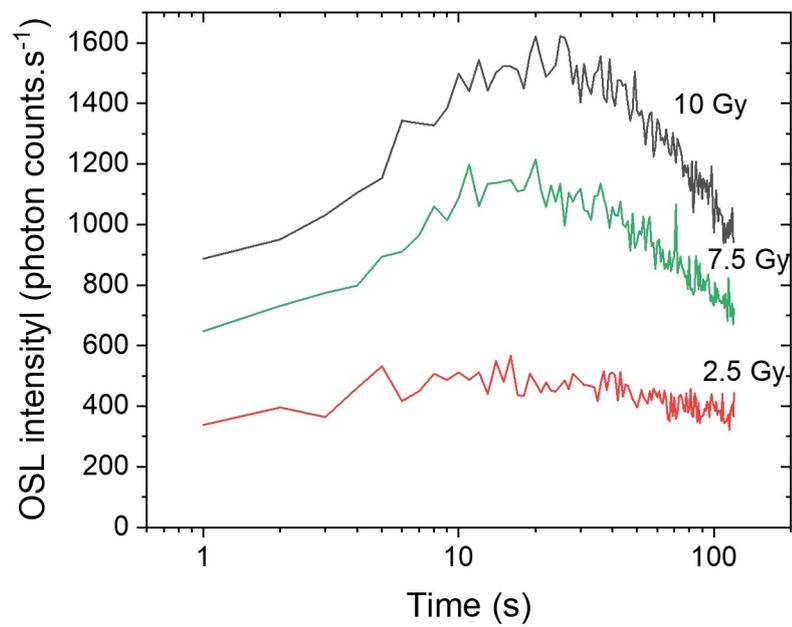
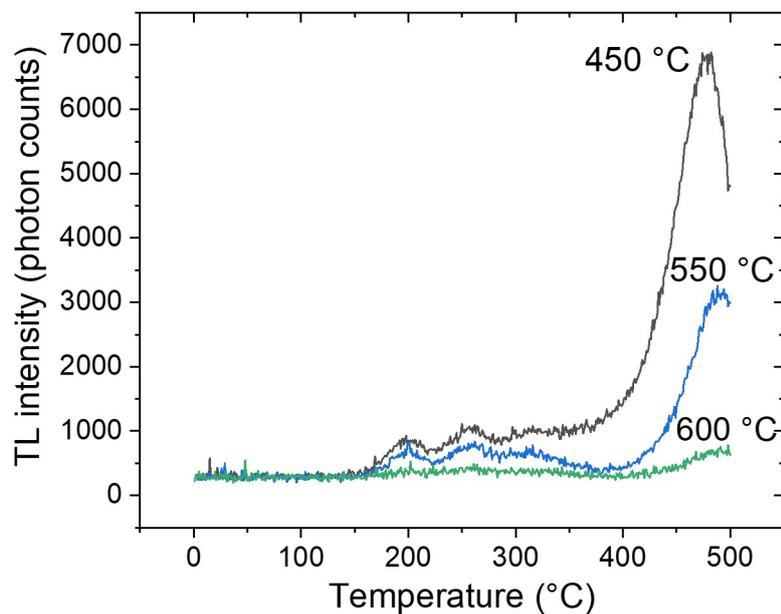
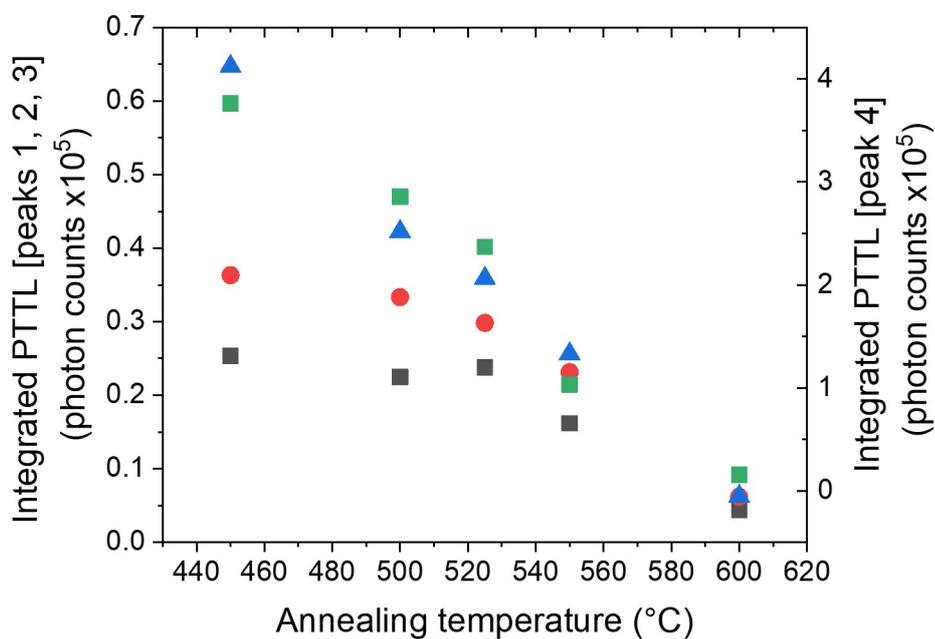


Fig. 5. Blue OSL recorded following β irradiation and 450 °C preheat (Step 3 , Table 1). Detection window : U-340.

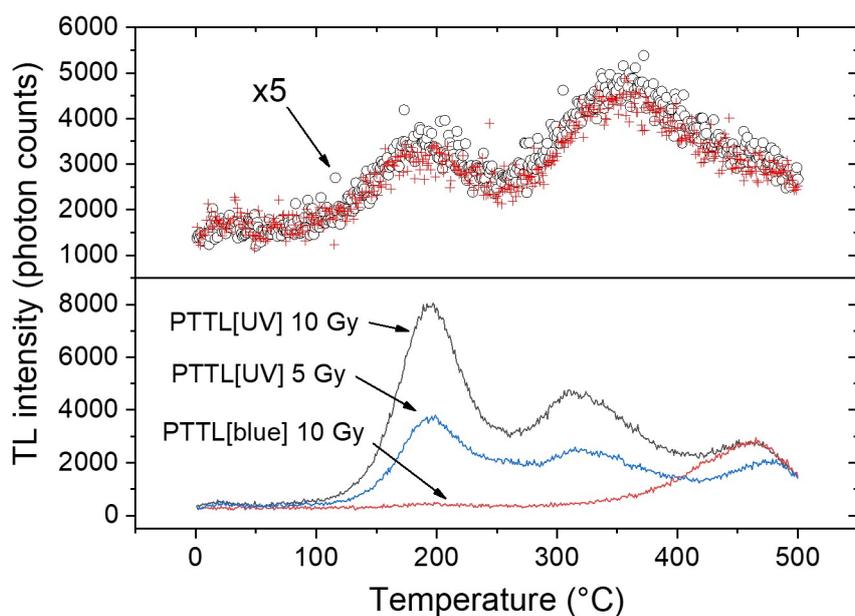


(a)

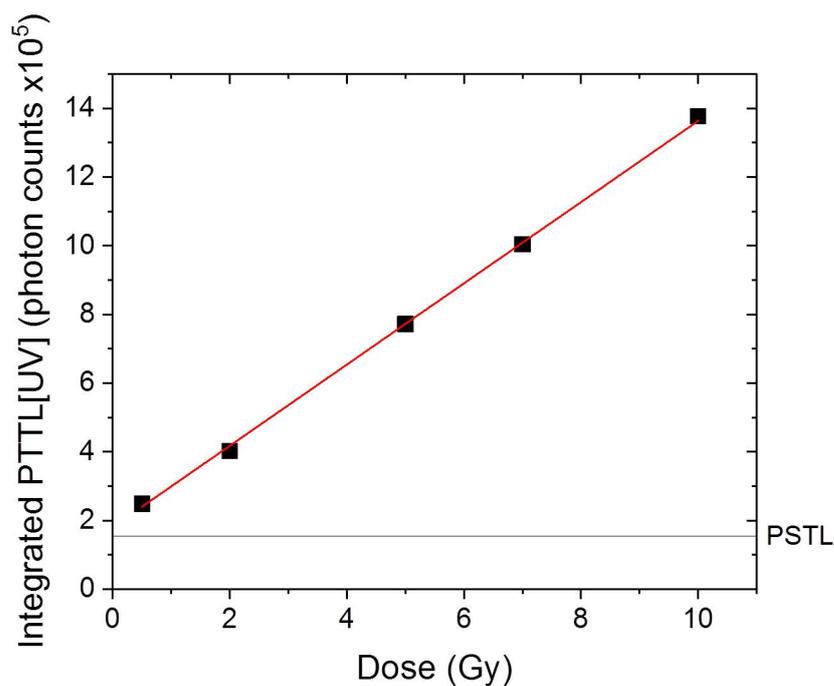


(b)

Fig. 6. PTTL [470 nm] glow curves of alumina substrate measured following β irradiation (10 Gy) and annealing at the indicated temperatures in the range 450-600 °C. b) PTTL vs annealing temperature: Peak 1 (integrated TL 150-223 °C, black filled squares), Peak 2 (223-284 °C, filled circles), Peak 3 (283-377 °C, blue filled triangles), and peak 4 (377-500 °C, green inverted filled triangles). Detection window: U-340. Heating rate: 0.5 °C·s⁻¹.



(a)



(b)

Fig. 7. a) Upper : native PSTL (black circles) and PSTL measured after a cycle of PTTL[UV] measurements and annealing at 900 °C (red crosses) of alumina substrate following UV illumination 2 minutes at room temperature. Lower : PTTL[UV] following β irradiation 10 Gy and 5 Gy (black and blue lines respectively), and PTTL[470 nm], 10 Gy β dose (red line). All illuminations were carried out at room temperature and the samples were exposed to light for 2 minutes. b) Integral of the PTTL (UV) signal (100-500 °C) vs administered β dose (0.5-10 Gy). The solid line represents a linear curve fitted to the experimental data; the horizontal line indicate the PSTL signal. Type A error in counts ≤ 1 %. Detection filter : U-340, heating rate : 0.5 °C.s⁻¹, Risø system.

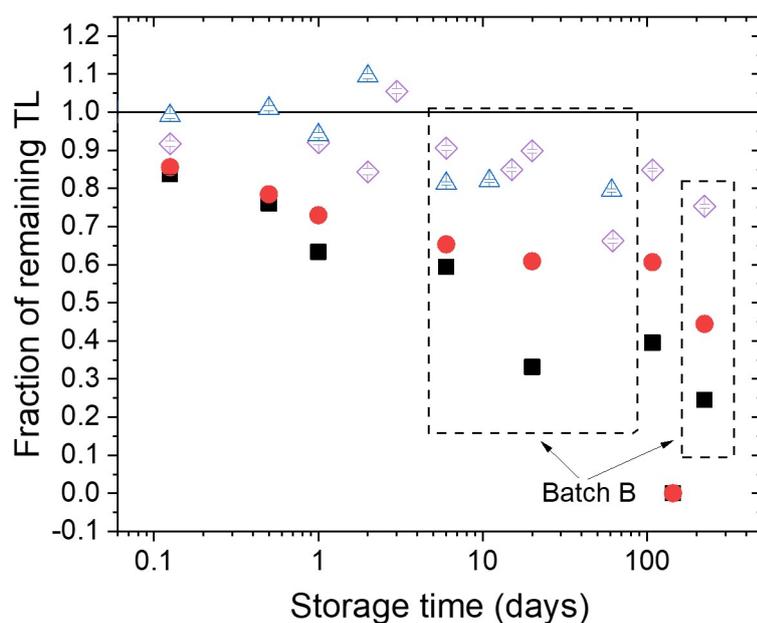


Fig. 8. Remaining PTTL signal (integral, 150-300 °C; purple diamonds: procedure A; blue triangles: procedure B) following storage (0.125- 224 d) in the dark at ambient temperature, compared with the remaining TL signal (integral, 150-200 °C, black squares; integral 200-300 °C, red circles). The horizontal line indicates the absence of fading ($y = 1$). The box (broken line) groups the results obtained with resistors drawn from combined batches 1 and 2.

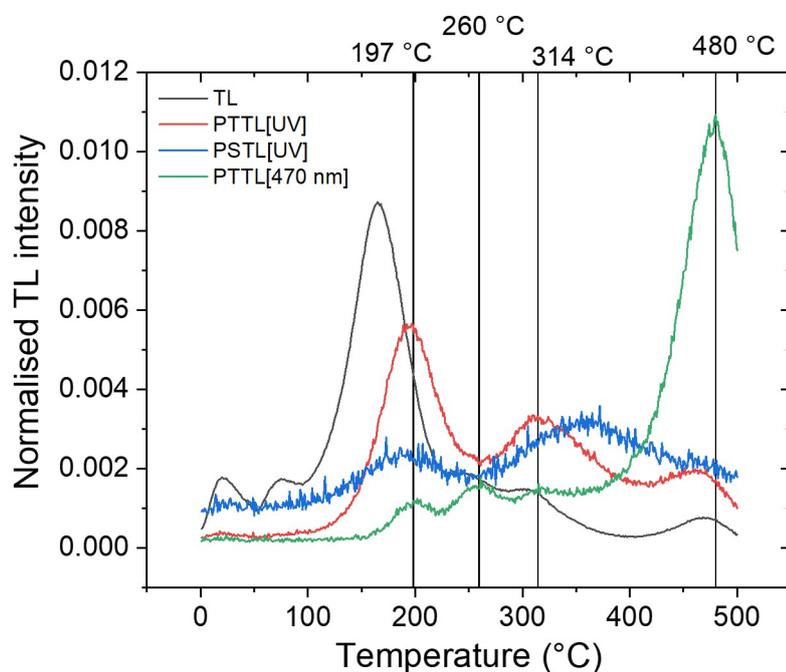


Fig. 9. Alumina substrate glow curves normalised by the number of counts of 1) TL, β dose 10 Gy (black line), 2) PTTL induced by a 2 min UV illumination at room temperature, β dose 10 Gy (red line), 3) photo-stimulate signal induced by a 2 min UV exposure at room temperature (no dose, blue line), and 4) PTTL induced by blue illumination 2 min at 150 °C, β dose 10 Gy (purple line). Some of the peak positions (197, 260, 314, and 480 °C) are indicated by a vertical line. The glow curves were normalised to the total integral of the signal. Risø system, U-340, detection window : U-340, heating rate : 0.5 °C·s⁻¹.

Research Highlights

- Phototransferred TL properties (PTTL) of alumina substrate (surface mount resistors) investigated for emergency dosimetry applications.
- The parameters of the illumination stage (temperature, duration, wavelength) influenced the PTTL emission.
- Supra-linear dose response and detection limit of 100 mGy using blue illumination; linear dose response and detection of 200 mGy if UV is used.
- Reduced rate of fading using PTTL compared to TL.